

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination BAE ET AL.	
	Examiner	Art Unit	Page 1 of 1
<b>U.S. PATENT DOCUMENTS</b>			

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B	US-6,506,650	01-2003	Yu, Bin	438/301
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M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.